

Fig. 1

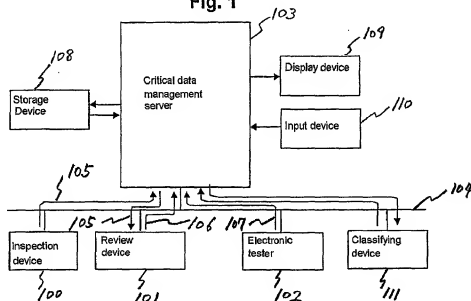


Fig. 3

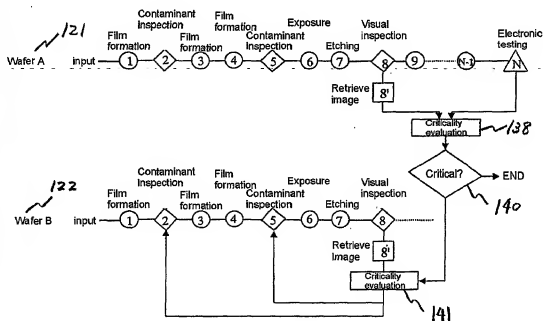


Fig. 2

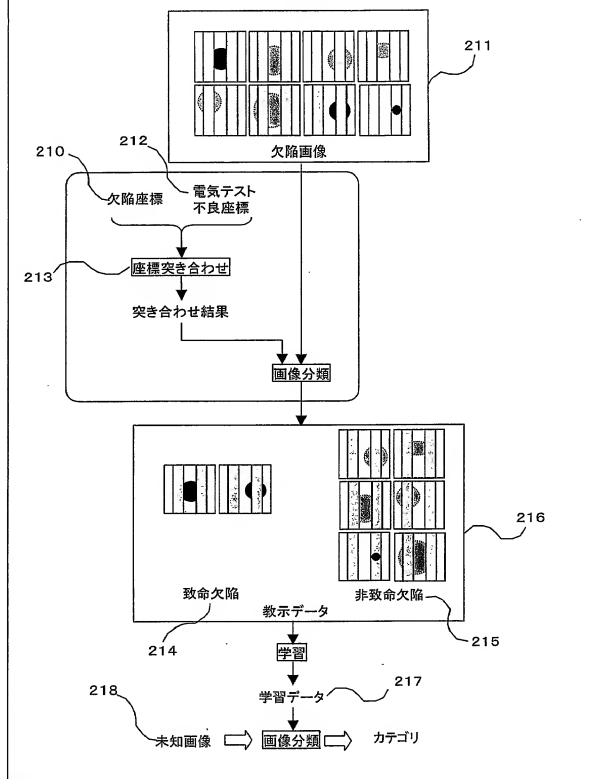


Fig. 4

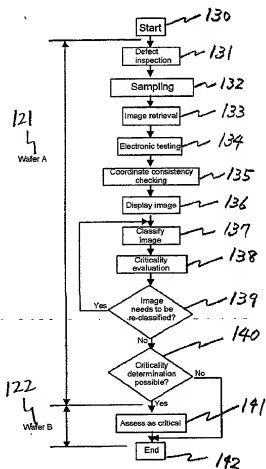


Fig. 5

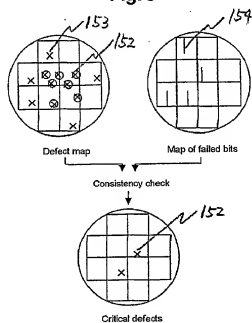


Fig. 6

Defect number	Chip coordinates	Defect coordinates	Sampling flag	Image name	Test result
1	(2,0)	($\Delta X1, \Delta Y1$)	0		G
2	(0,1)	($\Delta X2, \Delta Y2$)	0		G
3	(1,1)	($\Delta X3, \Delta Y3$)	1	image3	N
4	(2,1)	($\Delta X4, \Delta Y4$)	1	image4	N
5	(0,2)	($\Delta X5, \Delta Y5$)	0		G
6	(1,2)	($\Delta X6, \Delta Y6$)	1	image6	G
7	(1,2)	($\Delta X7, \Delta Y7$)	1	image7	G
8	(1,2)	($\Delta X8, \Delta Y8$)	1	image8	G
9	(2,2)	($\Delta X9, \Delta Y9$)	1	image9	N
10	(2,2)	($\Delta X10, \Delta Y10$)	1	image10	N
11	(3,2)	($\Delta X11, \Delta Y11$)	0		G
12	(1,3)	($\Delta X12, \Delta Y12$)	0		N

Fig. 7

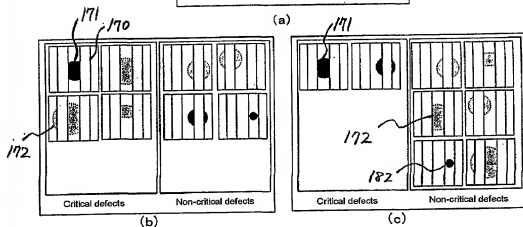
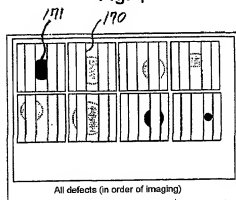


Fig. 9

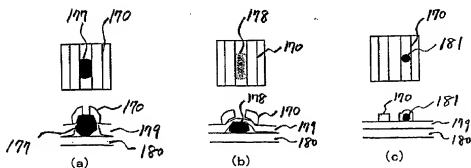
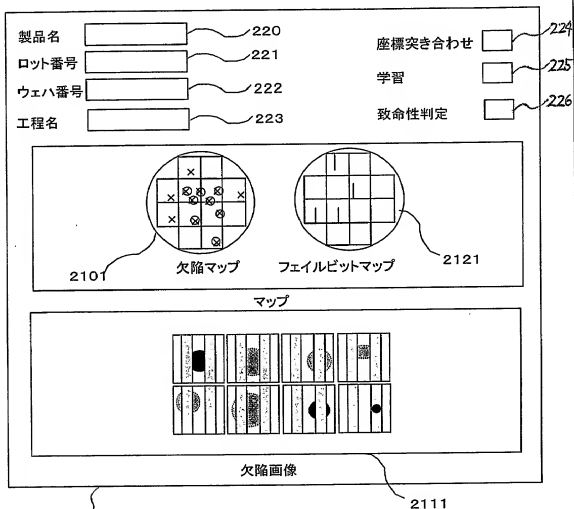


Fig. 8



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Fig. 10

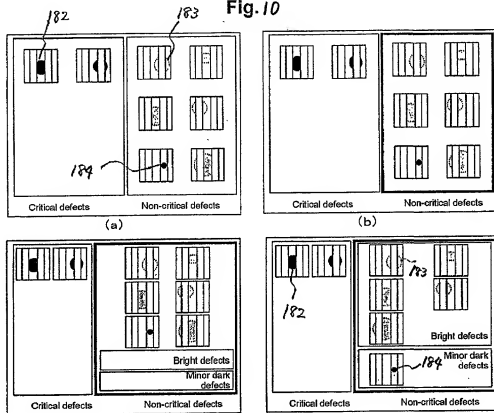


Fig. 11

Defect number	Chip coordinates	Defect coordinates	Sampling flag	Image name	Test result	Image classification
1	(2,0)	($\Delta X1, \Delta Y1$)	0		G	G
2	(0,1)	($\Delta X2, \Delta Y2$)	0		G	G
3	(1,1)	($\Delta X3, \Delta Y3$)	1	image3	N	N
4	(2,1)	($\Delta X4, \Delta Y4$)	1	image4	N	N
5	(0,2)	($\Delta X5, \Delta Y5$)	0		G	G
6	(1,2)	($\Delta X6, \Delta Y6$)	1	image6	G	G
7	(1,2)	($\Delta X7, \Delta Y7$)	1	image7	G	G
8	(1,2)	($\Delta X8, \Delta Y8$)	1	image8	G	G
9	(2,2)	($\Delta X9, \Delta Y9$)	(0)	image9	N	N
10	(2,2)	($\Delta X10, \Delta Y10$)	1	image10	N	N
11	(3,2)	($\Delta X11, \Delta Y11$)	0		G	G
12	(1,3)	($\Delta X12, \Delta Y12$)	0		N	N

Fig. 12

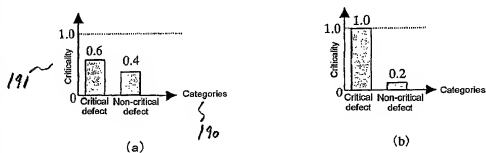


Fig. 13

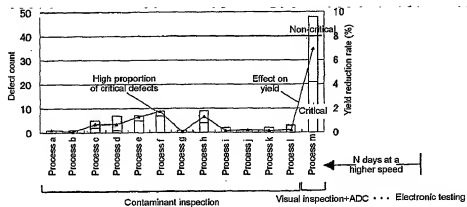


Fig. 14

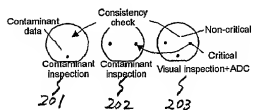
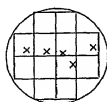
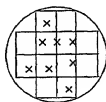


Fig. 15



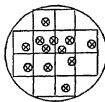
Inspection results 2

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Inspection results 5

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Sampling

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